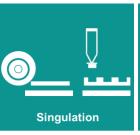
ABC development project





Singulation





Process description.

_Sawing of substrate and inspection and placement of devices



Features.

- _ Magazine load and offloading to Jedec tray
- _Dual pick & place mechanism
- _Dual chuck design and dual spindle, one blade / spindle
- _Vision system with reject units sorting function
- _Inspection includes (but no limited to): substrate orientation and substrate 2D code reader, device marking quality, broken devices, inked dot, package size X-Y, solder bumps quality,



SUBSTRATE SIZE: 178 x 127 mm (MAXIMUM)

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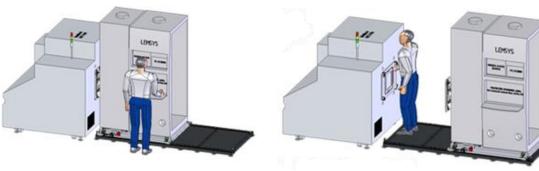


Final Test

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- Fully testing COOLiR²DIE at high current and voltage presents challenges for a test system and handler
 - Test team chose the LEMSYS test solution
 - Tester capability: 2000A/2000V for static and 2000A/1500V for dynamic testing
- The handler choice was limited due to the package size and exposed die
- Multitest selected with vertically docked pick & place handlers

 A custom manipulator from ESMO was required to provide a working interface on a "headless" LEMSYS tester



Undocked – moves on rails



LEMSYS Test

Docked

infineon

Packing





Process description.

_Transfer and inspection of singulated devices from Jedec tray to Tape & Reel packing



Features.

- _ 2D inspection system
- _Loading from Jedec tray or Tape & Reel
- _Output to Jedec tray or Tape & Reel
- _Statistics process control tool
- _10 head handler for high speed inspection
- _quadruple pick-and-place head for taping







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